Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/715,165	SHIEH ET AL.	
Examiner	Art Unit	
Donghee Kang	2811	

	CEAD	OUED	
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Class	Subclass	Date	Examiner
372	43-46,96	1/3/2005	KANG
257	94-96,98	1/4/2005	KANG
438	32,39,45	1/4/2005	KANG
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
east uspto,uspgpub,epo,jpo,dew,ibmtdb,	1/3/2005	KANG
text search see attached search history	1/3/2005	KANG
NPL IEEE explore	1/4/2005	KANG
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